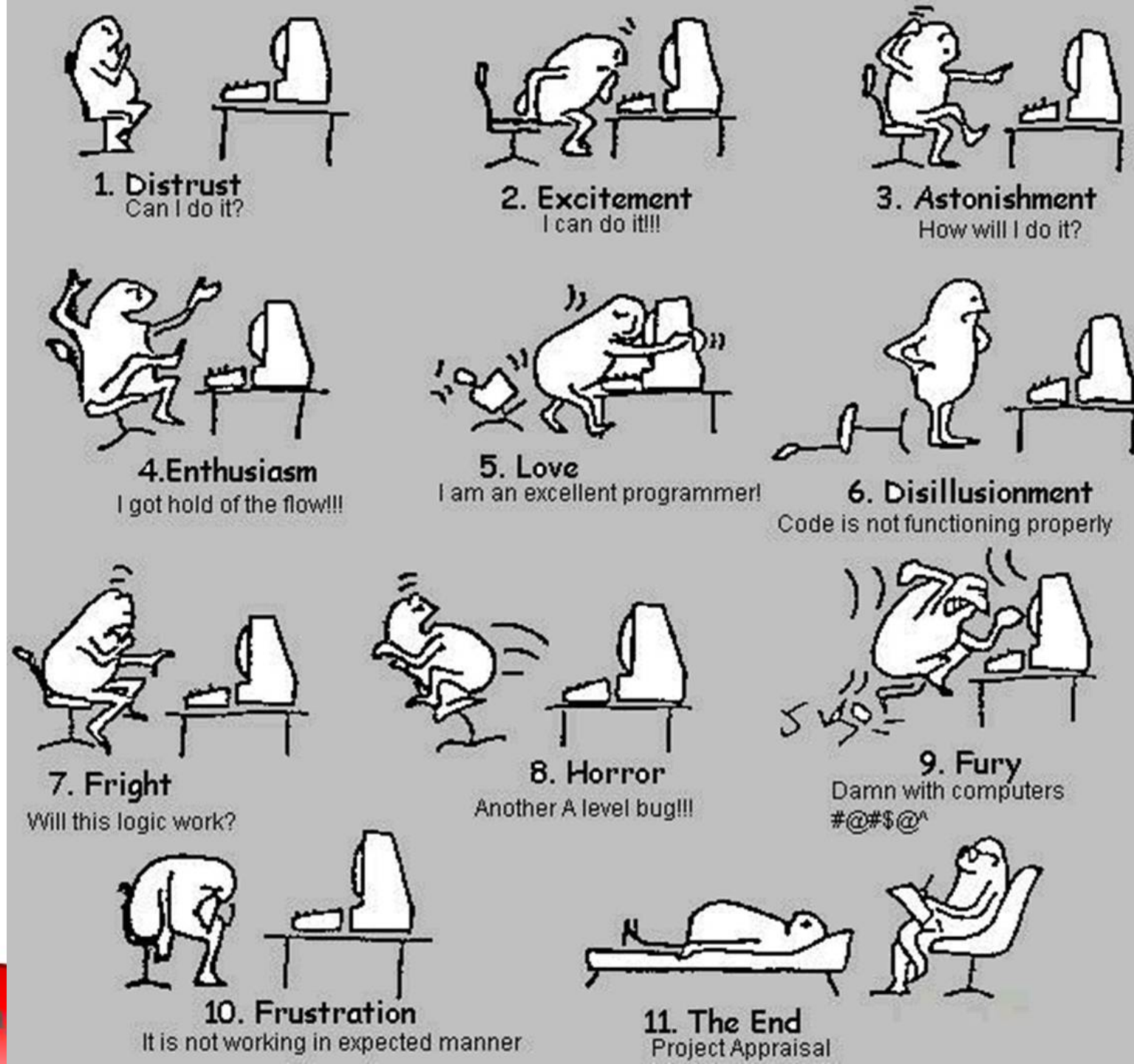


# IPS Debugging and Evaluation

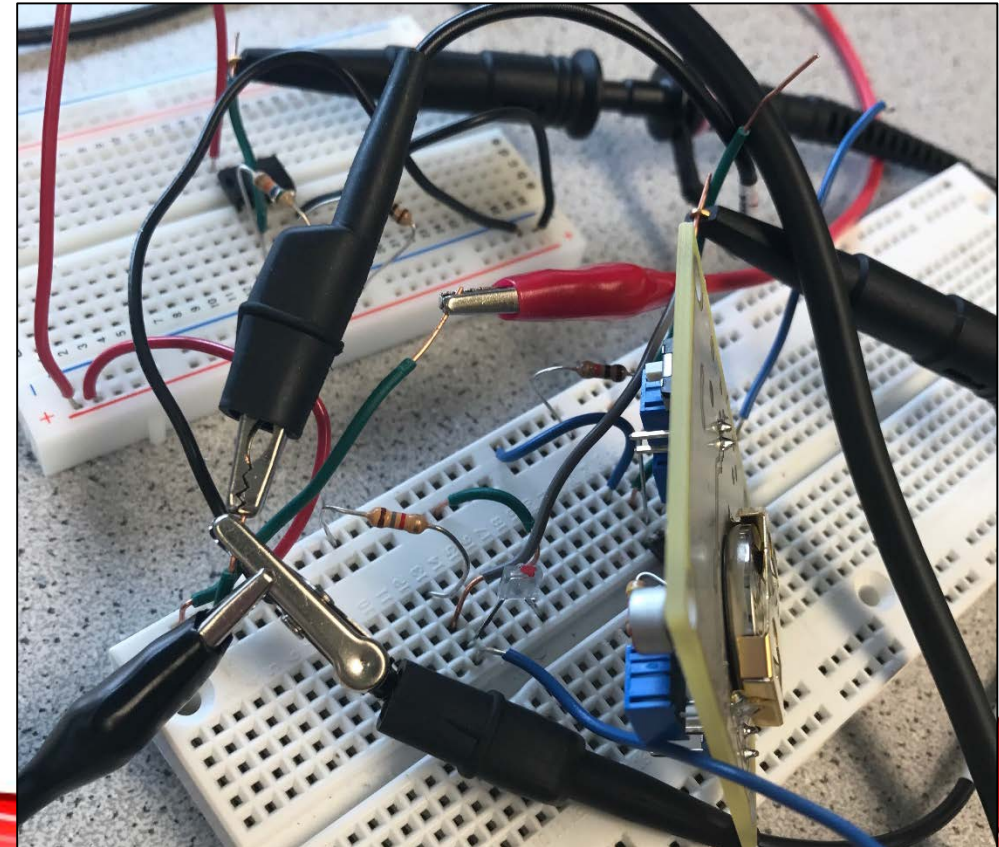


# Specification and Evaluation

## *Electronics*

- Sensitivity of IR sensors
  - Output vs. distance
  - SNR
  - Resistance to ambient light
- Sensitivity of microphone
  - Output vs. distance
- Bandwidth of communication
- Battery life time
  - (Under specific circumstance)
- Computation speed/memory
- Filters...
- Encoders...
- etc.

The One-ders, 2017



# Specification and Evaluation

## *Software*

- FFT
  - What is the Q of your filter?
- Search
  - How long does it take to find a path?
    - Worst case and best case scenarios
  - How does your implementation scale in time and memory with the size of the maze?

## *Mechanics*

- Speed/power of your servos
- Payload capability

# Evaluation

## *Intelligent Physical System*

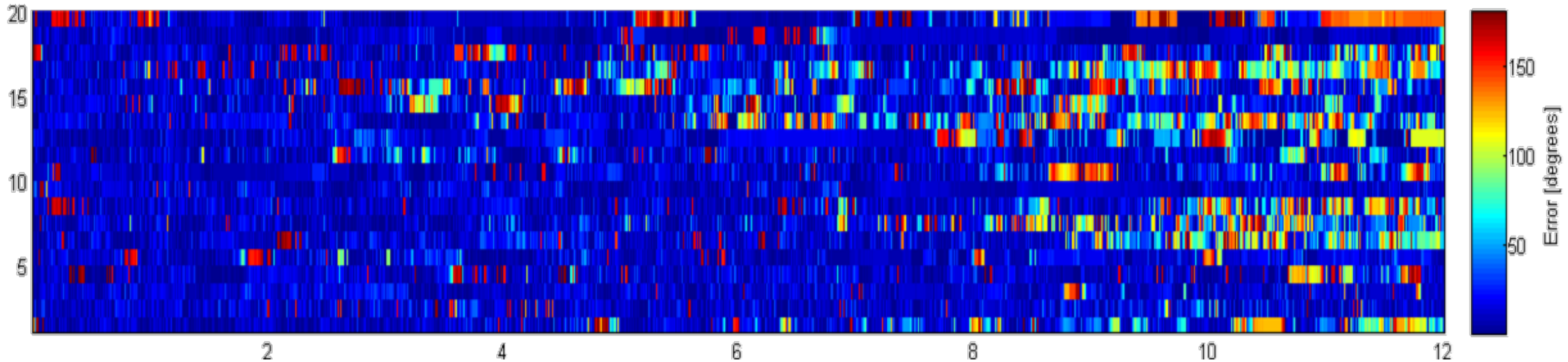
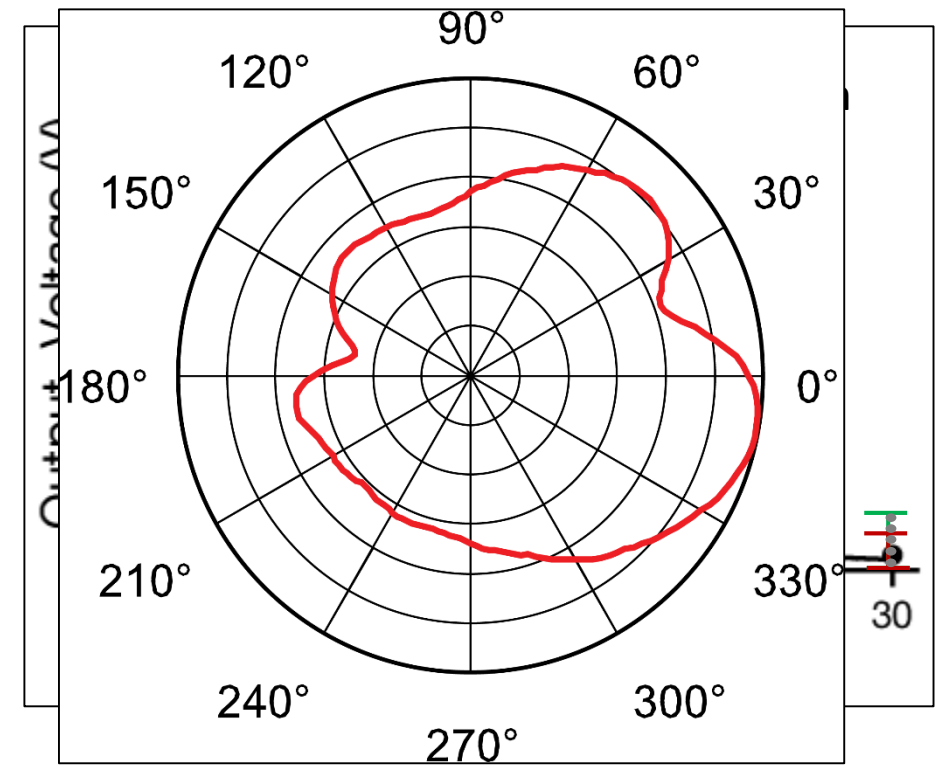
- Straight line velocity
- Turn speed, turn radius
- Reliability of grid traversal (straight/turn)
- Battery life time
  - Straight line test

### ***Standards***

- Help you compare different systems
- ...not that common in robotics
  - To help; be thorough in your evaluation, report negative results and reliability tests

# How to convey the information?

- Tables (max/min values)
- Graphs
  - with error bars
- Color maps
  - NB: BW printers/color blind people



# Debugging Intelligent Physical Systems

*Debugging is more complex than ever!*

- Electronics
- Software
- Mechanics
- Multiple connected devices
- Simulation

*Worst bugs are intermittent*

→ Apply a methodical and documented search



# Debugging Intelligent Physical Systems

MARK I Computer, Harvard, by Howard Aiken in 1944



# Debugging Intelligent Physical Systems

MARK I Computer, Harvard, by Howard Aiken in 1944



Admiral Grace Hopper, 1906-1992

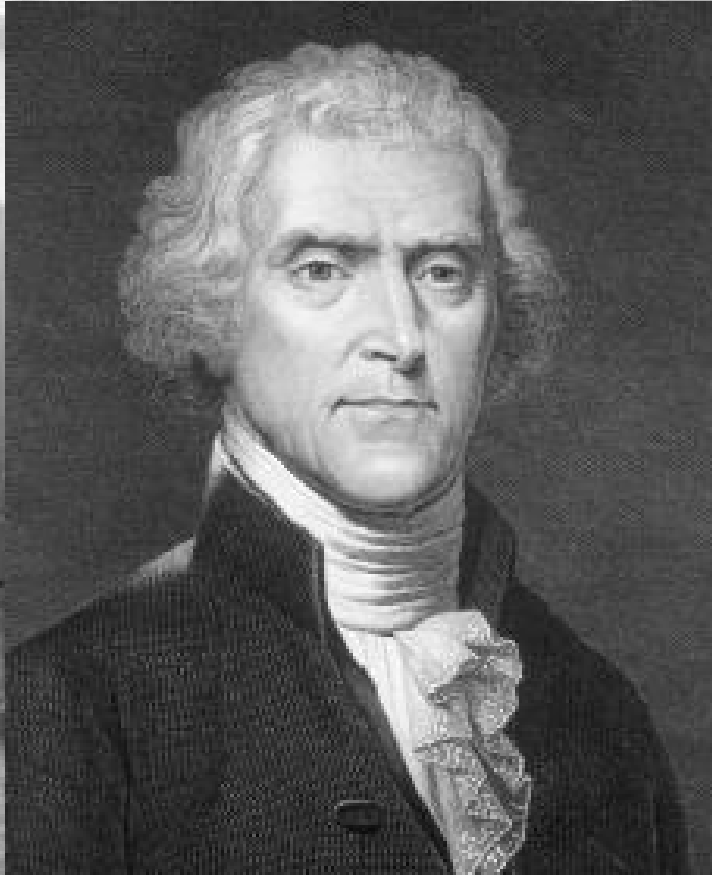




# Debugging Intelligent Physical Systems

MARK I Computer, Harvard, by Howard Aiken in 1944

Admiral Grace Hopper, 1906-1992



Thomas Jefferson 1878:

“Bugs' -- as such little faults and difficulties are called -- show themselves after months of intense watching, study and labor are requisite before commercial success or failure is certainly reached.”



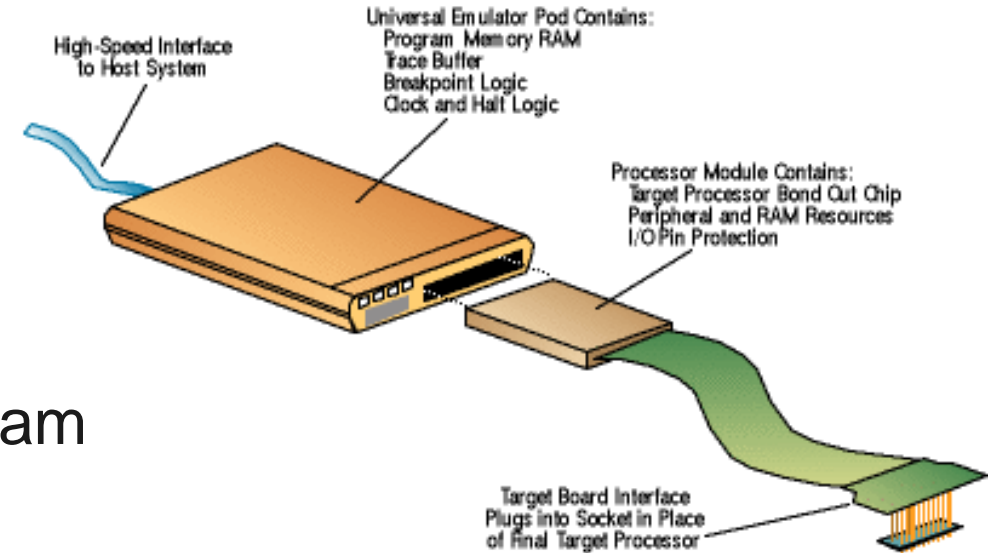
# Developing Your System

- Bottom-up development
  - Unit testing
  - Faster initial progress
- Top-down development
  - Implement every thing to begin with
  - Add dummy functions as placeholders
  - Leads to more modular products

# Software Debugging

- Compilers
  - Checks for low level errors such as
  - Syntax or type errors
  - Exception handling
- Software debuggers
  - Allows you to monitor the execution of a program
  - Stop it
  - Restart it
  - Set break points
  - Change values in memory
  - AVR Studio / Visual Micro debugger  
for the Atmel processors

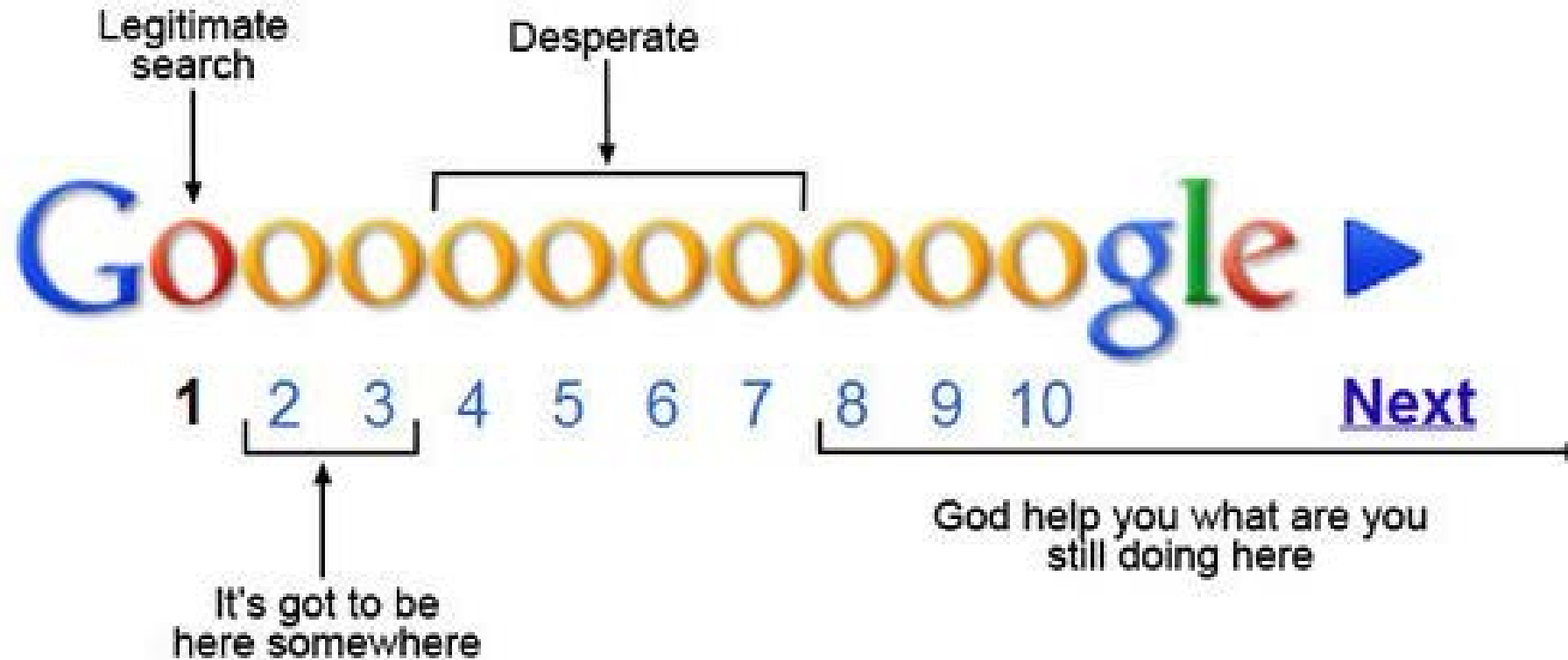
*Alternatively, use in-circuit emulators*



*Cheap, but slow...*

# Browsing for help online

EATLOVER.COM

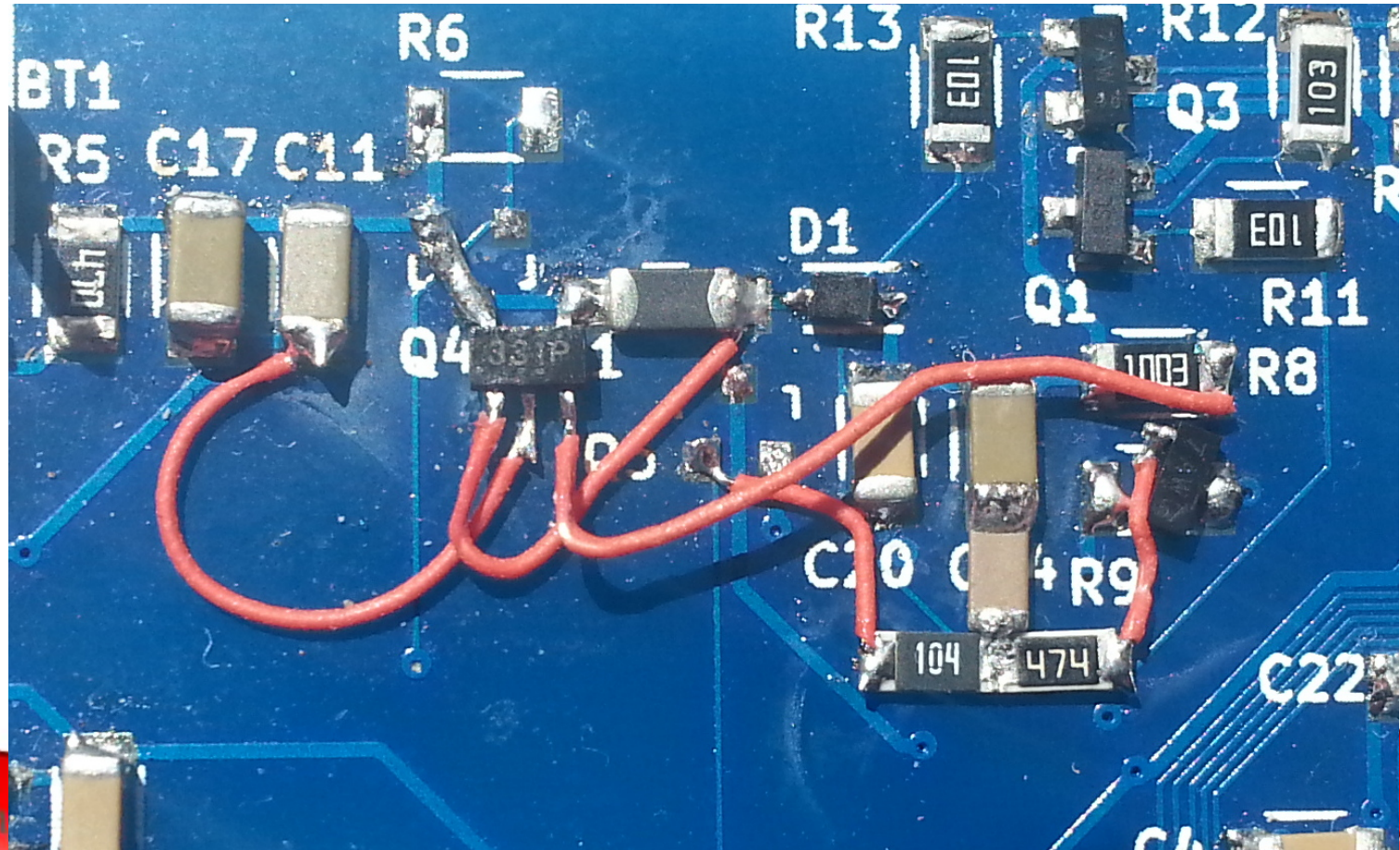


memecenter.com 

# PCB Debugging

- Always test circuit beforehand!
- Add test points
- Make circuit dividers
- Visual inspection
- Go/Nogo
- Test jig
- Automated Test Equipment

*time, price, thoroughness*



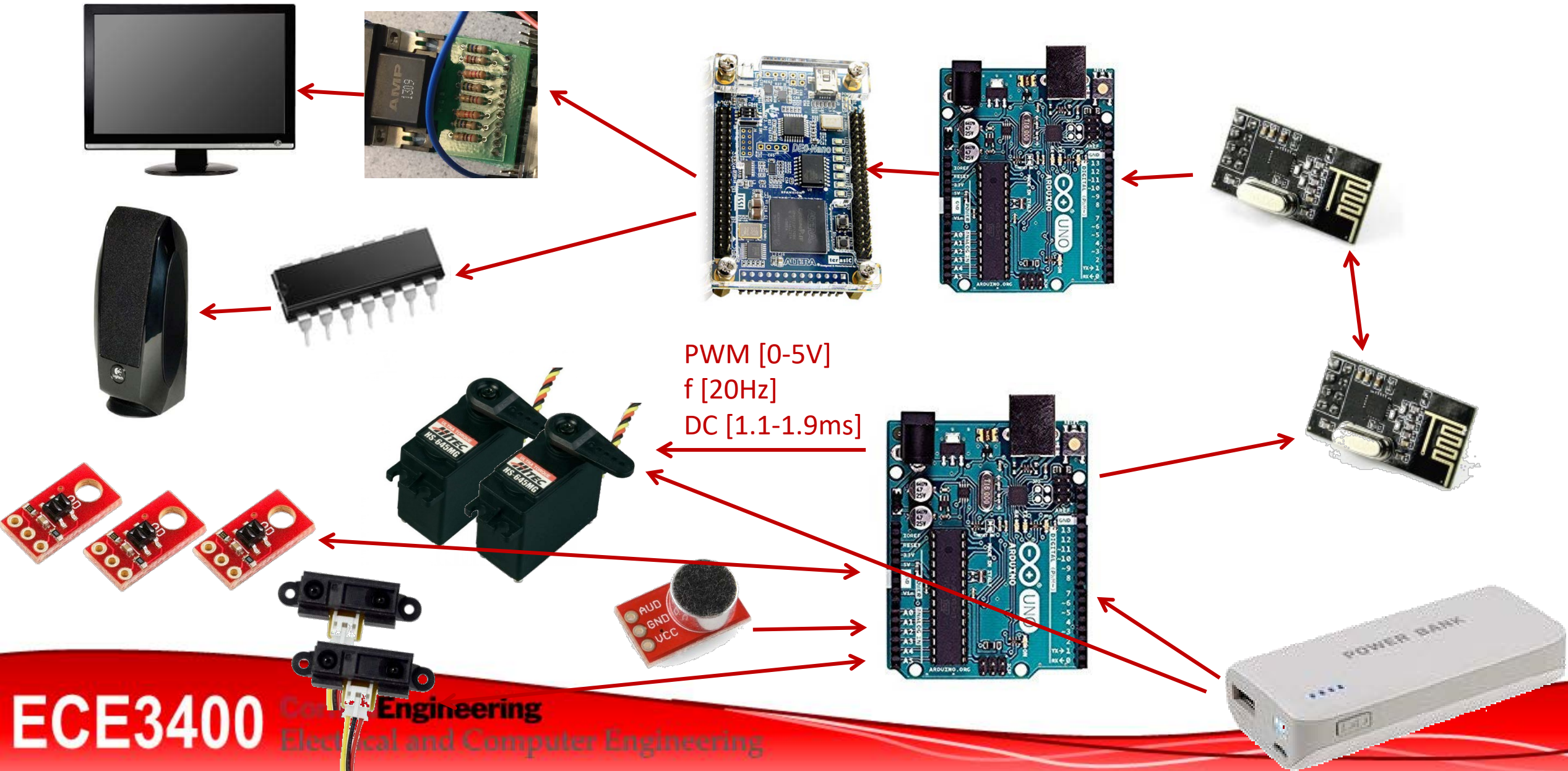
# Mechanical Bugs?

- Typically related to friction or jamming
- Broken teeth/dirt in gears
- Broken axels
- Fallen/obscured sensors
- Broken wires

*Errors leads to symptoms:*

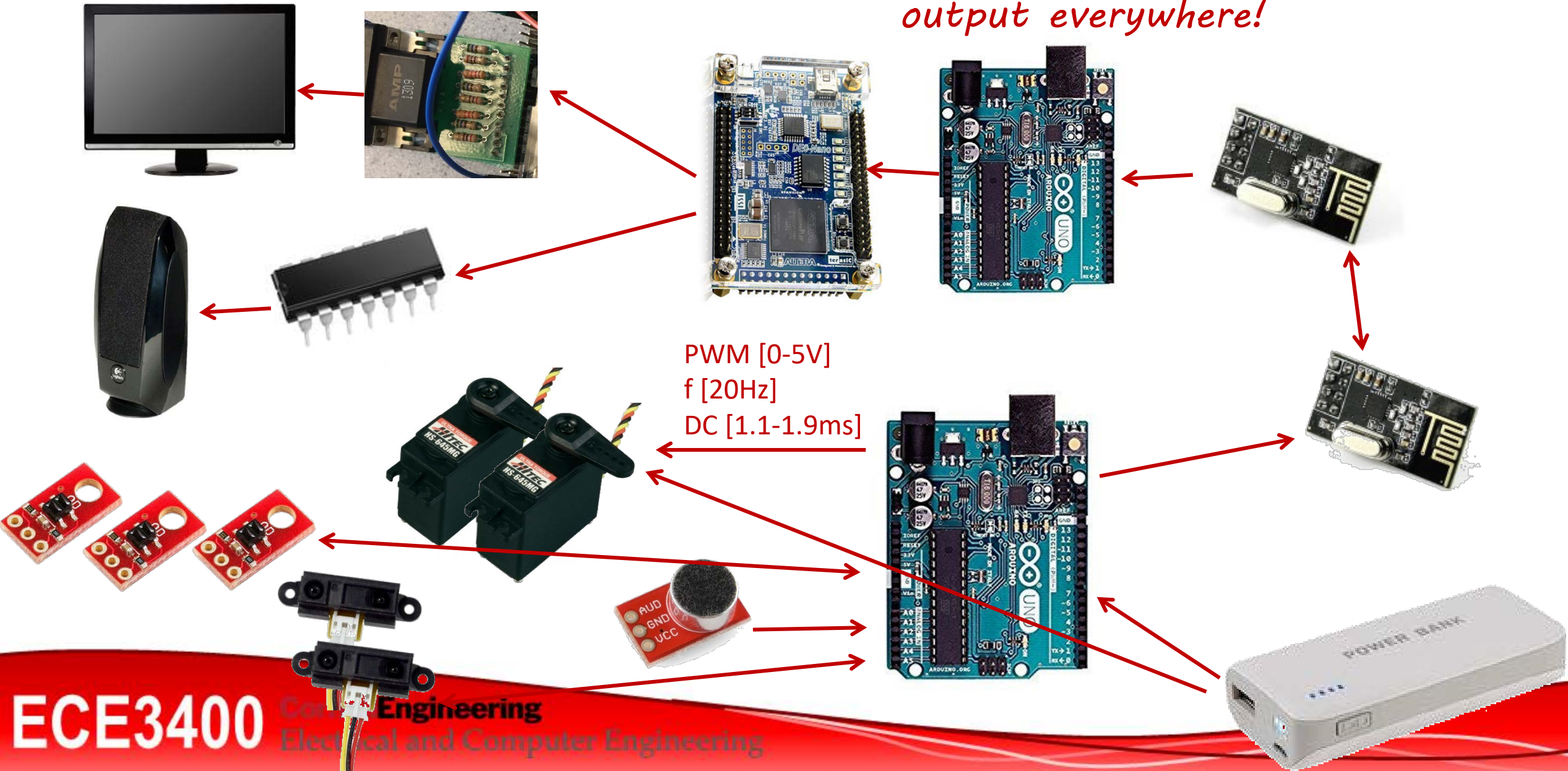
- Bad sensor values
- Slow/biased movement
- Jamming may cause power surges and reset conditions
- Make a test jig for the robot

# Map Your System , *then describe your interfaces!*



# Make a System Test

*Make a setup (code, environment) that generates a predictable output everywhere!*





# Debugging IPS

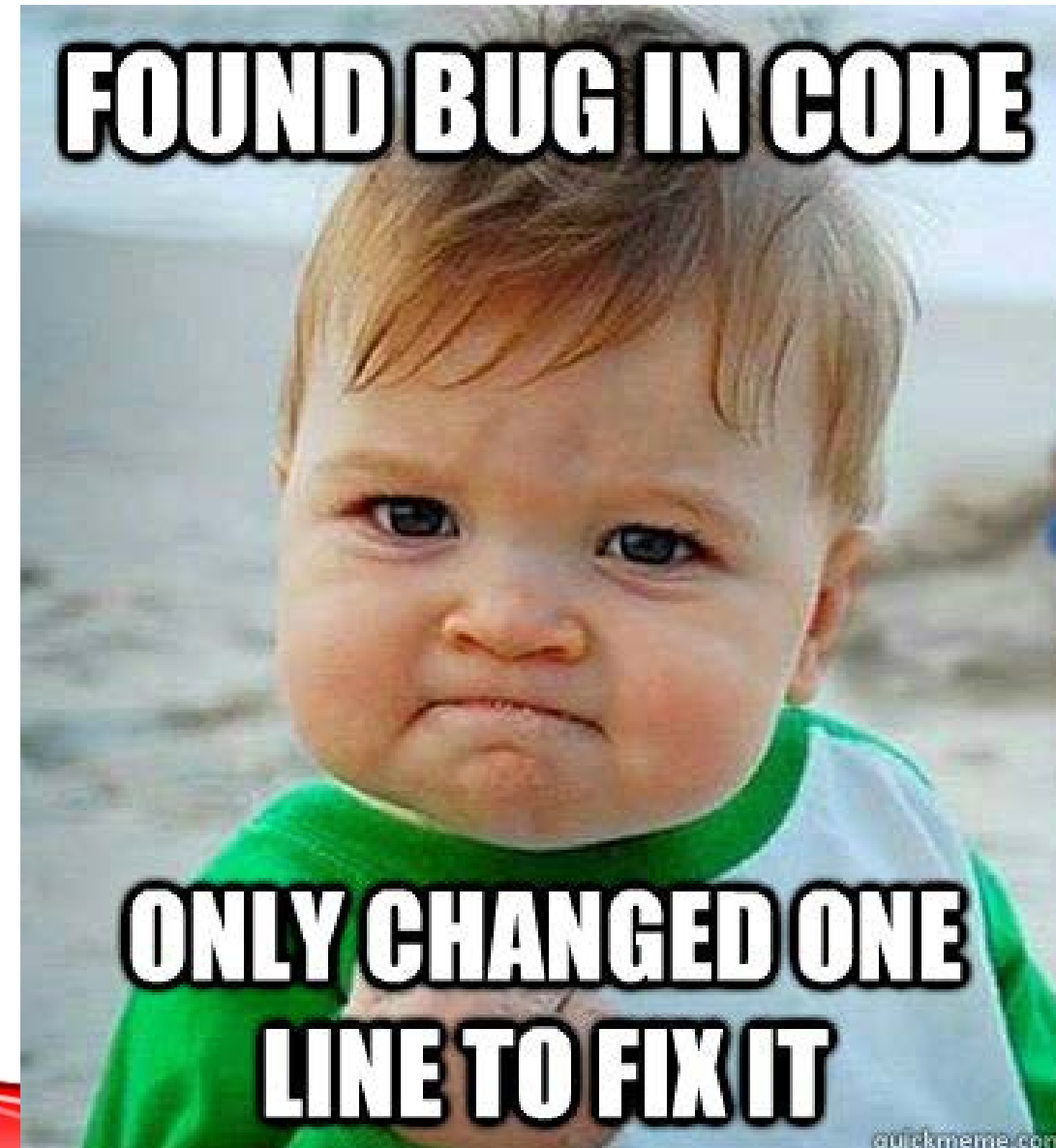
- STEP 1: Reproduce the symptom!
- STEP 2: Hunt down the bug
  - Brute force debugging
  - Problem simplification
  - Backtracking (start from problem)
  - Tracing or print debugging
  - Binary Search
  - Scientific Method: Form hypothesis and test it
  - Bug clustering



# Debugging IPS

## *Then solve the problem*

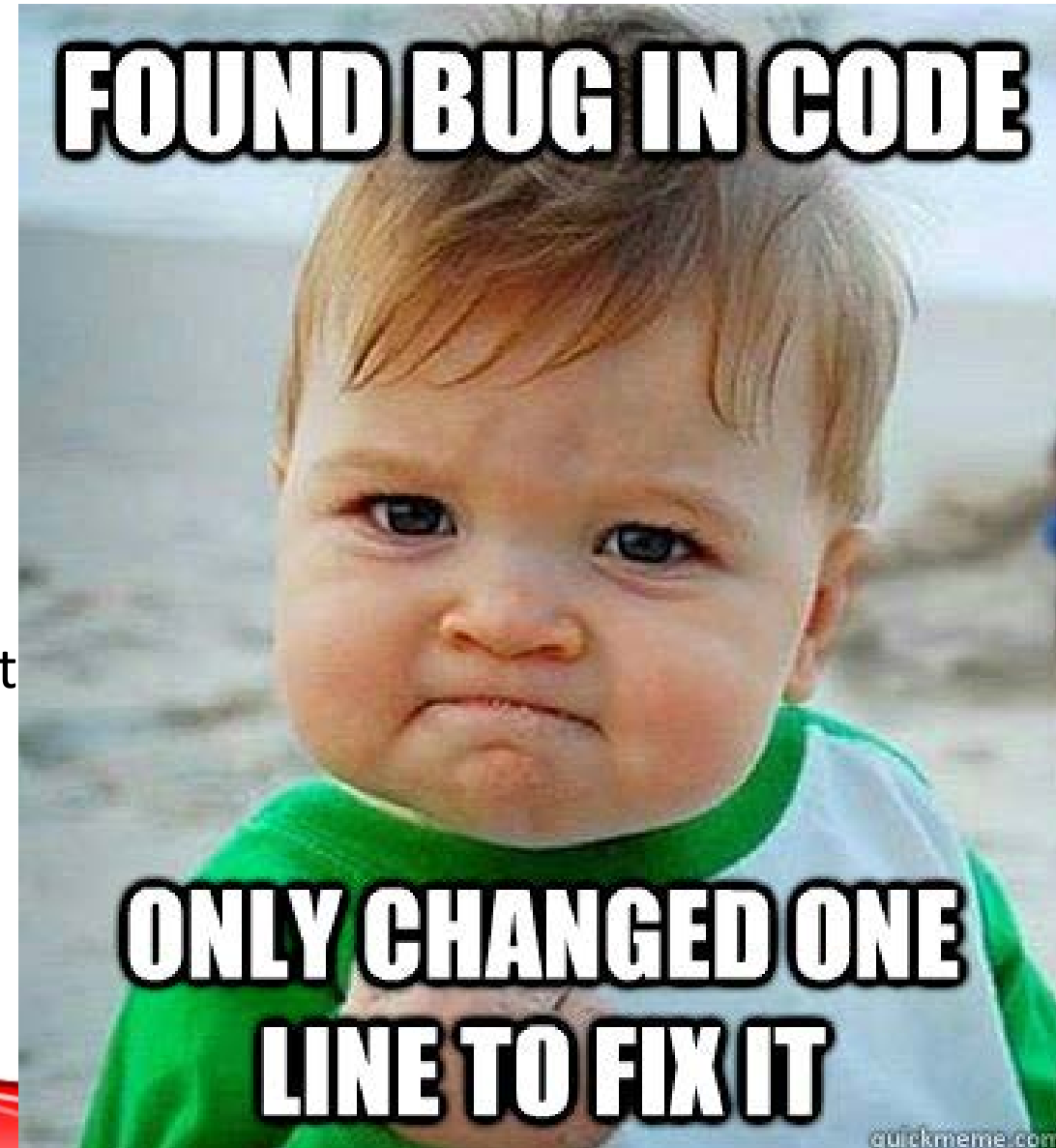
- In most cases the fix is simple
- Some times it is hard!
  - The error may be remote in space or time
  - Many errors may be present and correlated
  - Patch solutions?
    - Fixing one error may introduce new errors



# Debugging IPS

*Or try to prevent the bug in the first place*

- Clean code, electronics, wiring, mechanics
- Incremental development: Compile/test often!
- Instrument program to log information
- Instrument program with assertions
  - Always add else-statements
  - Always add default to switch case statement
  - Add value checkers
  - Add visible feedback (LEDs?)



# Mindset

- It appears hopeless, but there is a logical structure in there. The evidence may be obscure, but consistent in pointing to the guilty element.
- Don't panic -- be methodical. Often the TA is able to do this, and they don't know more about your code than you do.
- Discuss it with a team mate
- Sleep on it!



# Mindset

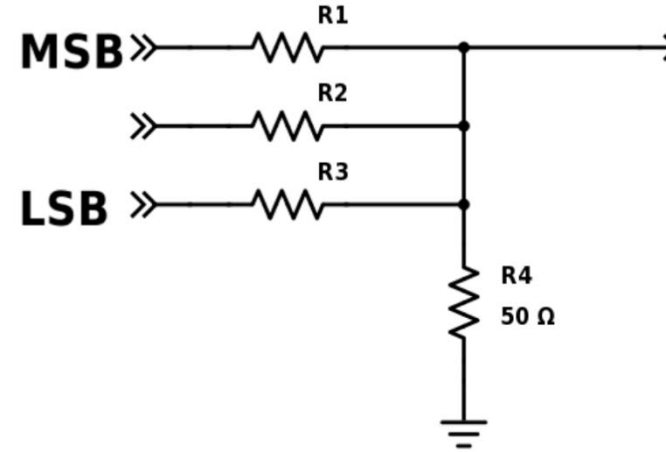
- Intuition and hunches are great— you just have to test them out. When a hunch and a fact collide, the fact wins.
- Don't look for complex explanations. Even the simplest omission or typo can lead to very weird behavior.
- The clue to what is wrong is in the values of your variables.
- Be systematic and persistent. The bug is not moving around in your system, trying to trick or evade you. It is just sitting in one place, doing the wrong thing in the same way every time.
- If your code was working a minute ago, but now it does not, what has changed?
- Do not change your code haphazardly trying to track down the bug.
- Fix bugs immediately (even if they're not the original bug, they may be correlated).



# Calculating the Resistor Values of the DAC

*\*Courtesy of Team 9-10*

3-bit Signal	Voltage value
000	0V
001	1/7 V
010	2/7 V
011	3/7 V
100	4/7 V
101	5/7 V
110	6/7 V
111	1 V



$$\frac{3.3V - 1V}{R_{eq}} = \frac{1V - 0V}{50\Omega}$$

$$R_{eq} = \frac{(3.3V - 1.0V) \cdot 50\Omega}{1V} = 115\Omega$$

$$\frac{1}{R_{eq}} = \frac{1}{R_1} + \frac{1}{R_2} + \frac{1}{R_3} = \frac{1}{R_1} + \frac{1}{2 \cdot R_1} + \frac{1}{4 \cdot R_1} = \frac{4 + 2 + 1}{4 \cdot R_1} = \frac{7}{4 \cdot R_1}$$

$$R_1 = \frac{7}{4} \cdot R_{eq} = \frac{7 \cdot 115\Omega}{4} = 201.25\Omega \Rightarrow R_2 = 2 \cdot R_1 = 402.50\Omega \Rightarrow R_3 = 2 \cdot R_2 = 805\Omega$$

# E Series Resistor Values

E3

- 3 values in each decade:  $1\Omega$ ,  $2.2\Omega$ ,  $4.7\Omega$
- Tolerance:  $\pm 40\%$

E6

- 6 values in each decade:  $1\Omega$ ,  $1.5\Omega$ ,  $2.2\Omega$ ,  $3.3\Omega$ ,  $4.7\Omega$ ,  $6.8\Omega$
- Tolerance:  $\pm 20\%$

E12

- 12 values in each decade:  
 $1\Omega$ ,  $1.2\Omega$ ,  $1.5\Omega$ ,  $1.8\Omega$ ,  $2.2\Omega$ ,  $2.7\Omega$ ,  $3.3\Omega$ ,  $3.9\Omega$ ,  $4.7\Omega$ ,  $5.6\Omega$ ,  $6.8\Omega$ ,  $8.2\Omega$
- Tolerance:  $\pm 10\%$

etc...

$$R1 = 270\Omega$$

$$R2 = 561\Omega$$

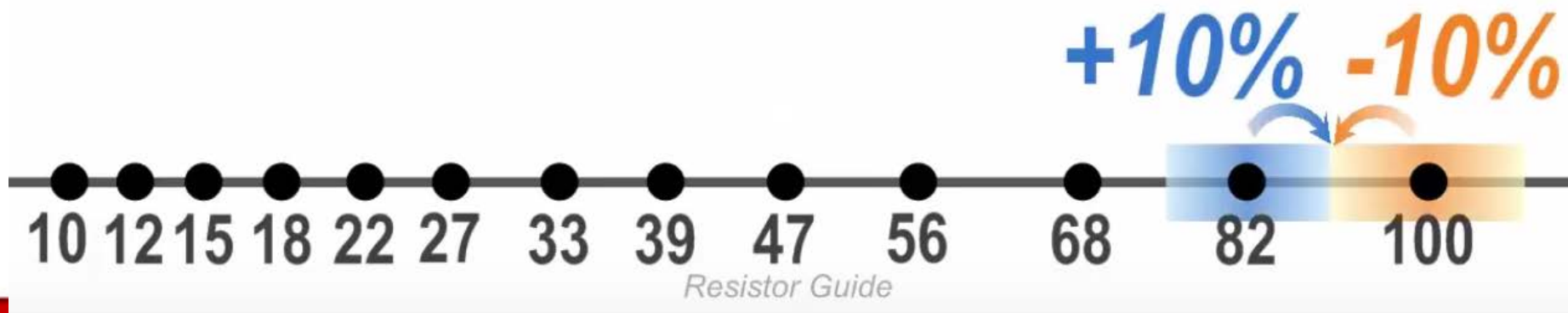
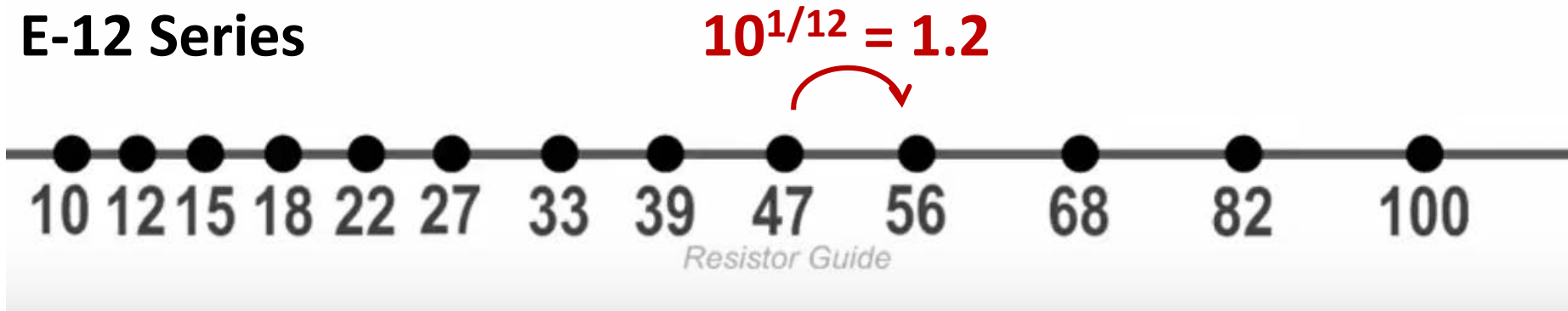
$$R3 = 1200\Omega$$

# E Series Resistor Values

- Equally spaced out on a logarithmic scale
- Current tolerances are typically 5%, 1-2%

**R1 = 270Ω**  
**R2 = 561Ω**  
**R3 = 1200Ω**

## E-12 Series

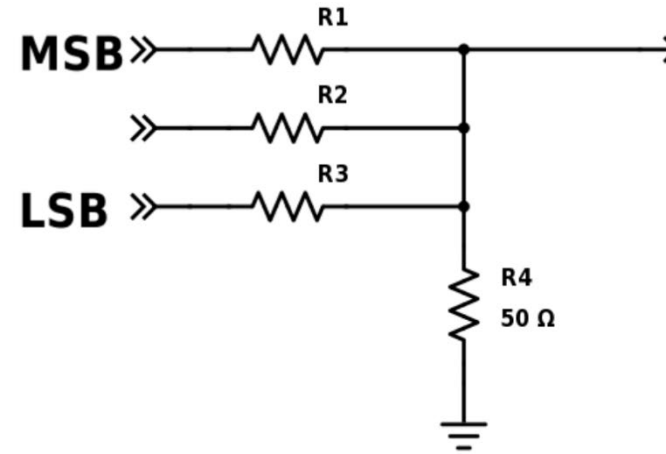




# Calculating the Resistor Values of the DAC

**R1 = 270Ω**  
**R2 = 561Ω**  
**R3 = 1200Ω**

3-bit Signal	Voltage value
000	0V
001	0.1428 V
010	0.2857 V
011	0.4285 V
100	0.5714 V
101	0.7142 V
110	0.8571 V
111	1 V



0X1 →  $3.3V \cdot [50\Omega \parallel R1] / [R3 + (50\Omega \parallel R1)]$   
 $= 3.3V \cdot 42.2\Omega / (1200\Omega + 42.2\Omega) = 0.11V$

X01 →  $3.3V \cdot [50\Omega \parallel R2] / [R3 + (50\Omega \parallel R2)]$   
 $= 3.3V \cdot 46.0\Omega / (1200\Omega + 46.0\Omega) = 0.12V$

XX1 →  $3.3V \cdot 50\Omega / [R3 + 50\Omega]$   
 $= 3.3V \cdot 50\Omega / (1200\Omega + 50\Omega) = 0.132V$

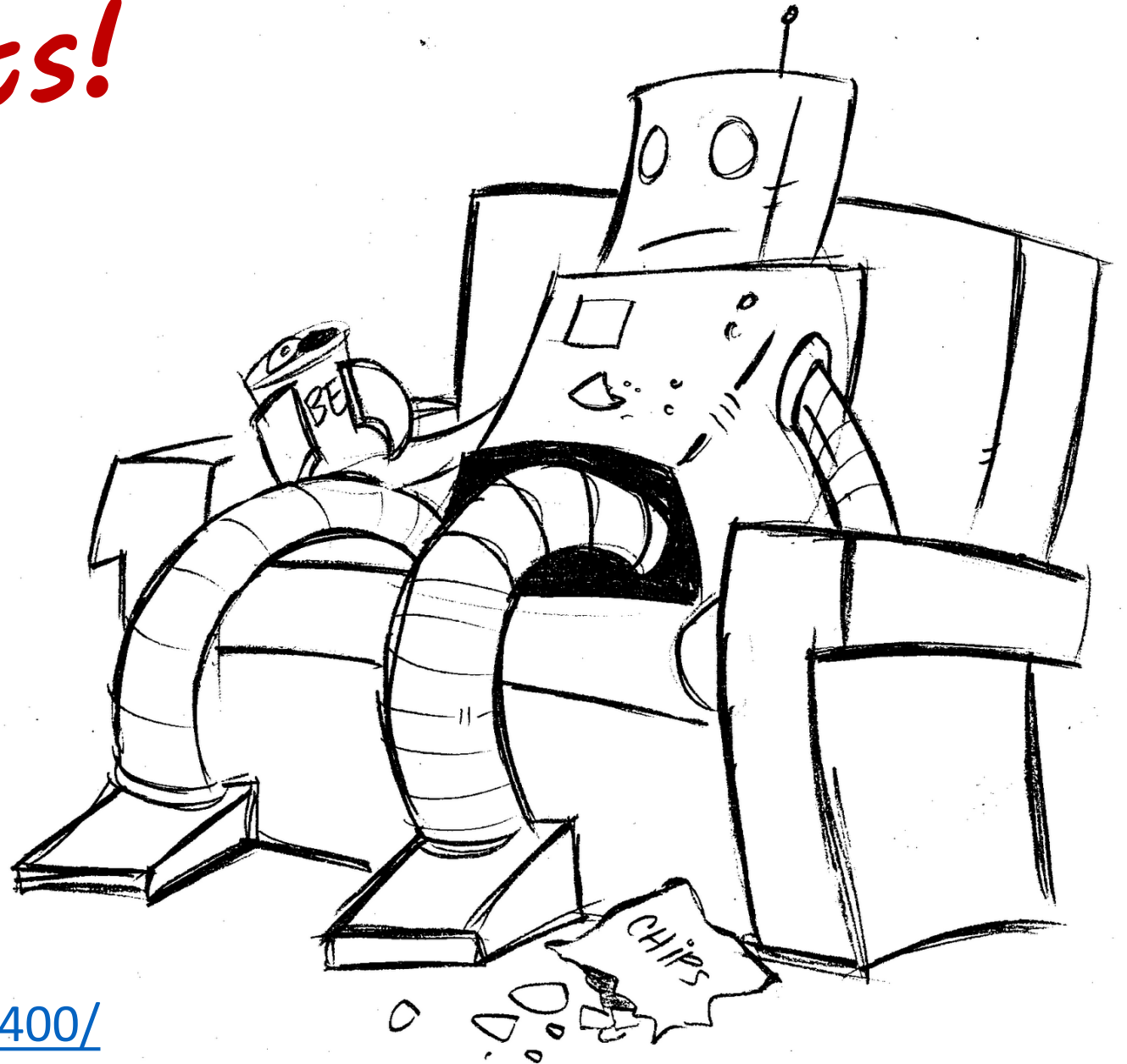
## Tristate pins:

- Set pins to inputs!

## **Logistics:**

- **Next week**
- **Ethics!**
  - **Lectures and Homework**

# Go Build Robots!



Class website: <https://cei-lab.github.io/ece3400/>

Piazza: <https://piazza.com/cornell/fall2017/ece3400/home>